

## CLAIMS

1-36. (canceled)

37. (currently amended) Circuitry including an electrical over stress (EOS) shunt connected between a first rail and a second rail of the circuitry, the EOS shunt comprising:  
a switchable low-resistance path connected between the first and second rails; and  
a voltage threshold detector comprising a plurality of series-connected diodes connected in series with a resistor between the first and second rails, wherein:  
the voltage threshold detector is coupled to turn on and off the switchable low-resistance path based on relative voltage levels of the first and second rails; [[and]]  
the voltage threshold detector further comprises at least one switch connected to selectively bypass at least one of the series-connected diodes; and  
the resistor is a programmable resistor whose resistance can be selectively changed when the at least one series-connected diode is bypassed.

38. (previously presented) The circuitry of claim 37, wherein:  
the first rail is a power rail; and  
the second rail is a ground rail.

39. (previously presented) The circuitry of claim 37, wherein the circuitry is implemented in a single integrated circuit.

40. (previously presented) The circuitry of claim 37, further comprising an electrostatic discharge (ESD) shunt connected between the first and second rails in parallel with the EOS shunt, wherein:  
the ESD shunt is designed to protect the circuitry from ESD events; and  
the EOS shunt is designed to protect the circuitry from EOS events having durations longer than the ESD events.

41. (previously presented) The circuitry of claim 37, wherein bypassing one or more of the series-connected diodes changes the relative voltage levels at which the switchable low-resistance path is turned on.

1           42.     (previously presented) The circuitry of claim 37, wherein the voltage threshold detector  
2 comprises at least two switches connected to selectively bypass up to at least two of the series-connected  
3 diodes.

1           43.     (canceled)

1           44.     (previously presented) The circuitry of claim 37, wherein the EOS shunt further  
2 comprises a driver connected between the voltage threshold detector and the switchable low-resistance  
3 path.

1           45.     (previously presented) The circuitry of claim 44, wherein the driver comprises one or  
2 more series-connected inverters.

1           46.     (previously presented) The circuitry of claim 37, wherein the switchable low-resistance  
2 path comprises a transistor whose channel is connected between the first and second rails and whose gate  
3 is coupled to the voltage threshold detector.

1           47.     (previously presented) The circuitry of claim 37, further comprising a Firewire IEEE  
2 1394 interface.

1           48.     (currently amended) The circuitry of claim 37, wherein:  
2 the first rail is a power rail;  
3 the second rail is a ground rail;  
4 the circuitry is implemented in a single integrated circuit;  
5 the circuitry further comprises an ESD shunt connected between the first and second rails in  
6 parallel with the EOS shunt, wherein:  
7                 the ESD shunt is designed to protect the circuitry from ESD events; and  
8                 the EOS shunt is designed to protect the circuitry from EOS events having durations  
9 longer than the ESD events;  
10            bypassing one or more of the series-connected diodes changes the relative voltage levels at which  
11 the switchable low-resistance path is turned on;  
12            ~~the resistor is a programmable resistor whose resistance can be selectively changed when the at~~  
13 ~~least one series-connected diode is bypassed;~~

14           the EOS shunt further comprises a driver connected between the voltage threshold detector and  
15   the switchable low-resistance path, wherein the driver comprises one or more series-connected inverters;  
16   and  
17           the switchable low-resistance path comprises a transistor whose channel is connected between the  
18   first and second rails and whose gate is coupled to the voltage threshold detector.

1           49.     (previously presented) The circuitry of claim 48, wherein the voltage threshold detector  
2   comprises at least two switches connected to selectively bypass up to at least two of the series-connected  
3   diodes.

1           50.     (previously presented) The circuitry of claim 48, further comprising a Firewire IEEE  
2   1394 interface.